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PATENT & TRADEMARK OFFICE

FIG.1

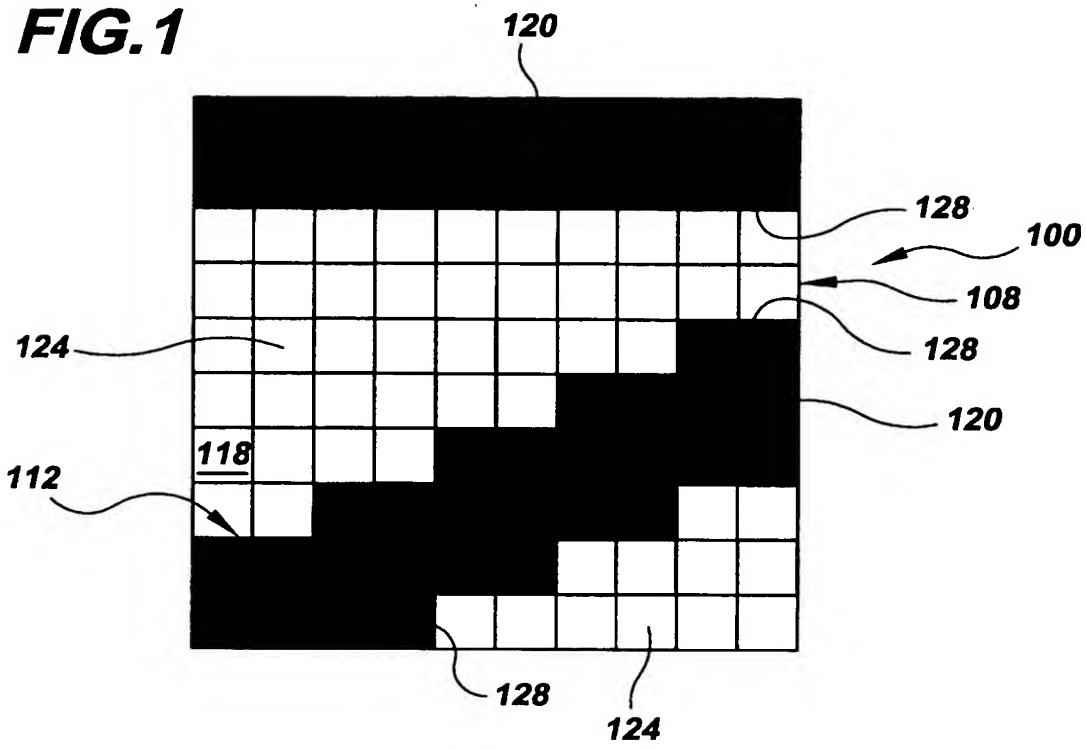
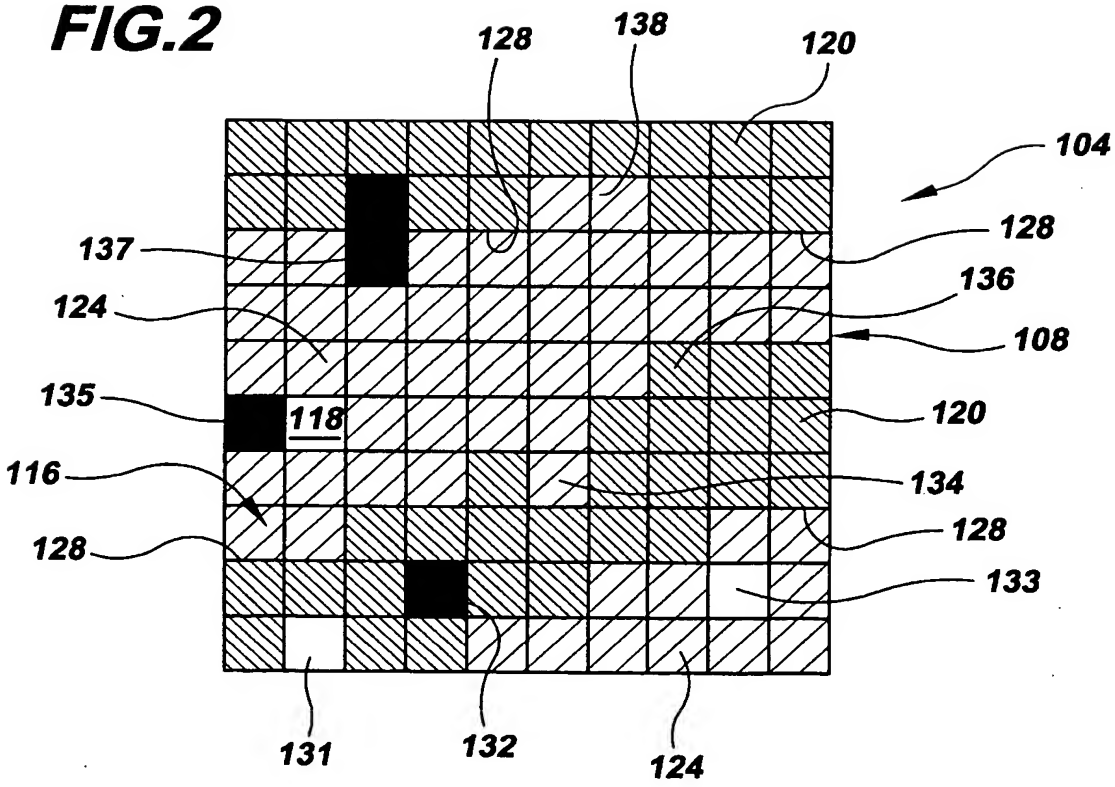


FIG.2



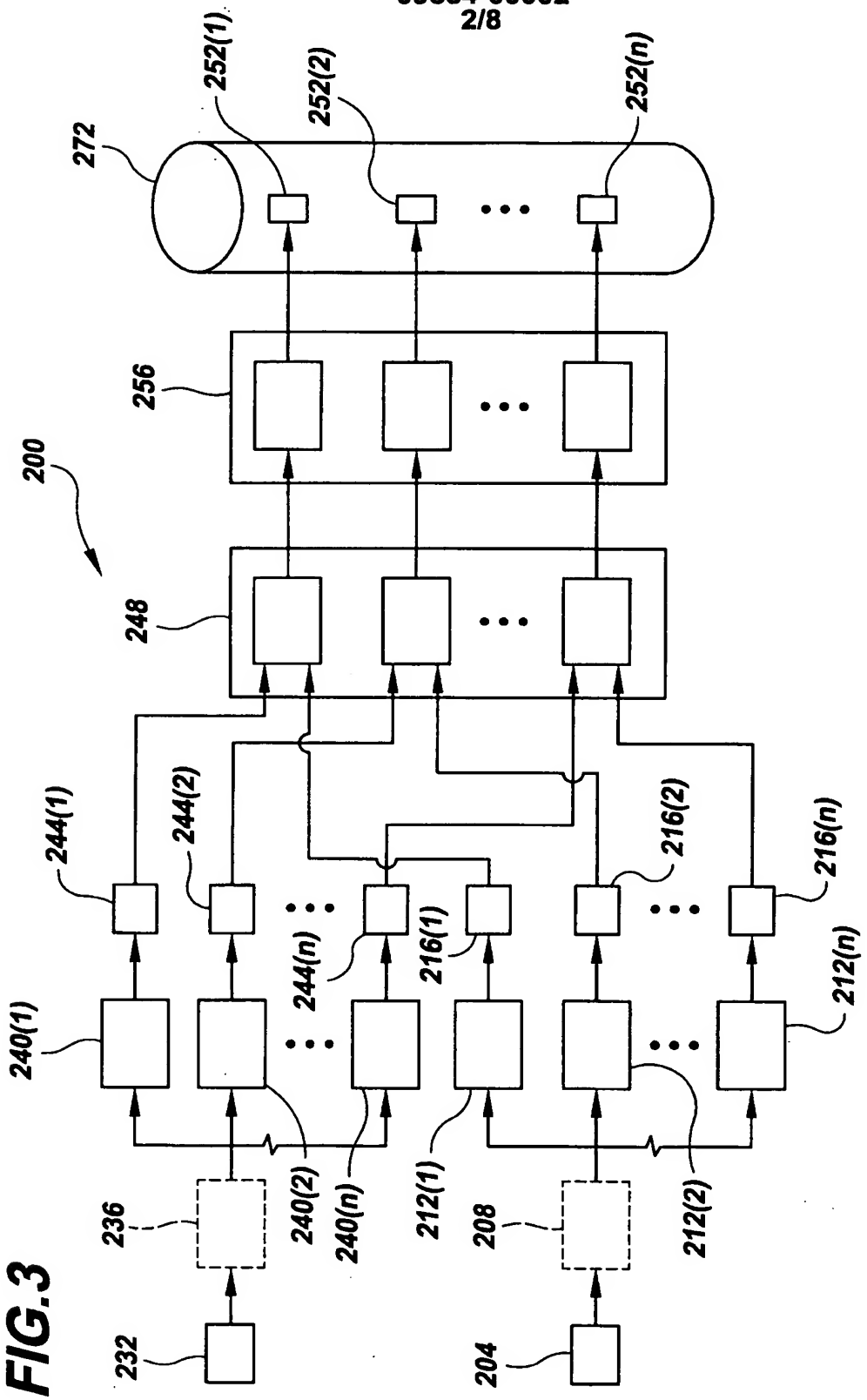

272
252(1)
252(2)
252(n)
256
200
248
244(1)
244(2)
244(n)
216(1)
216(2)
216(n)
240(1)
240(2)
240(n)
212(1)
212(2)
212(n)
236
208
232
204

FIG.3

FIG.4A

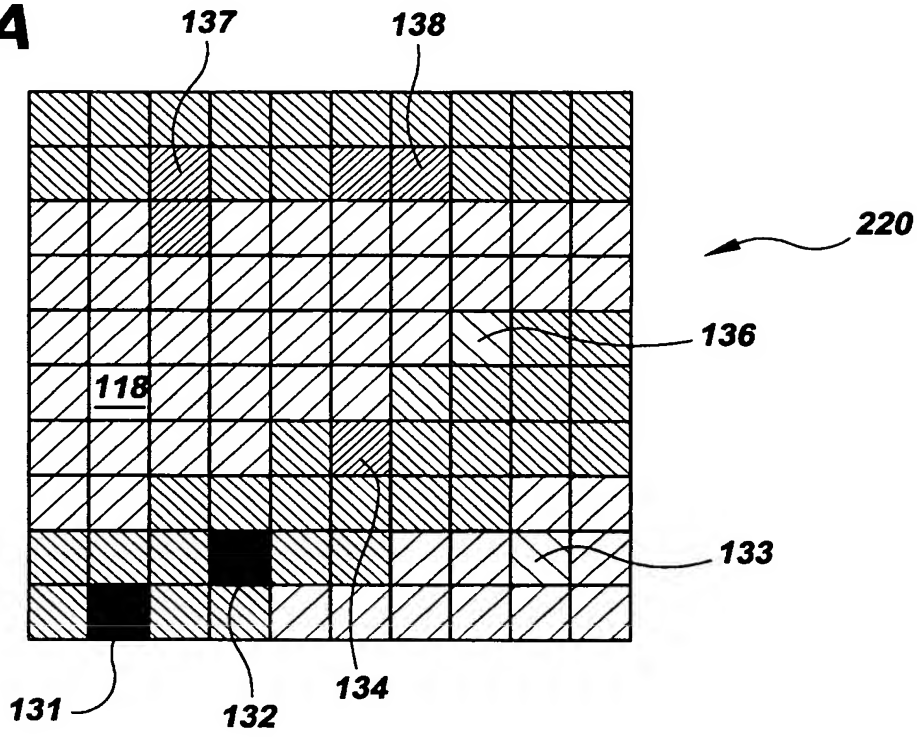

137
138
220
136
118
133
131
132
134

FIG.4B

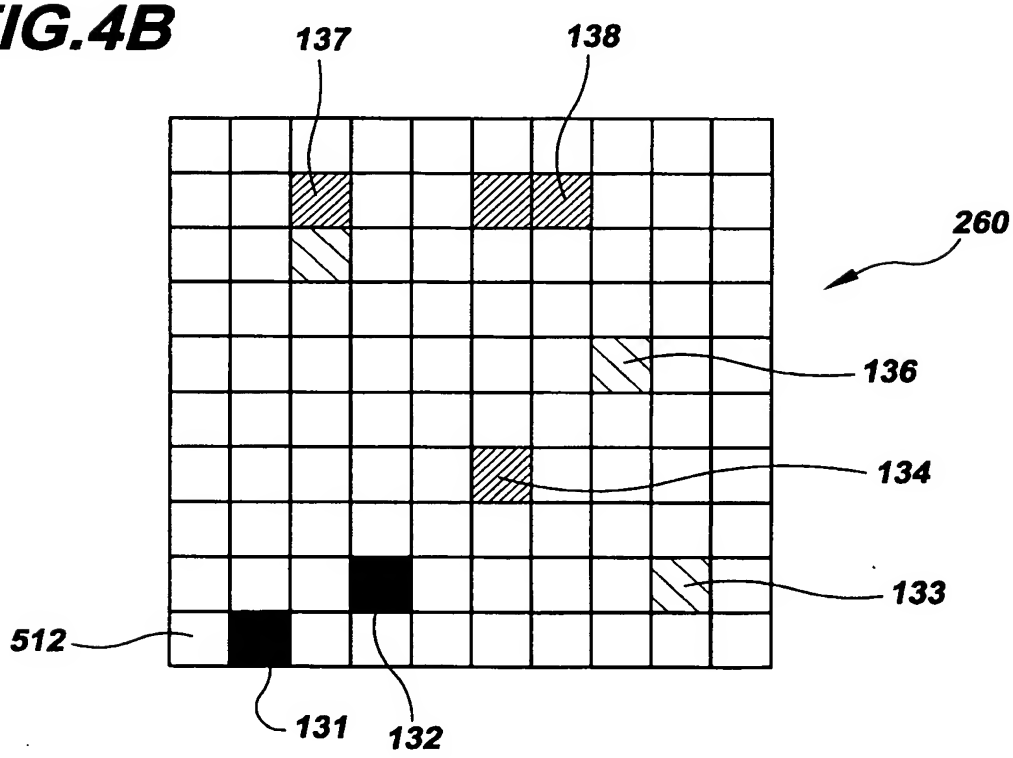

137
138
260
136
134
133
512
131
132

FIG.5A

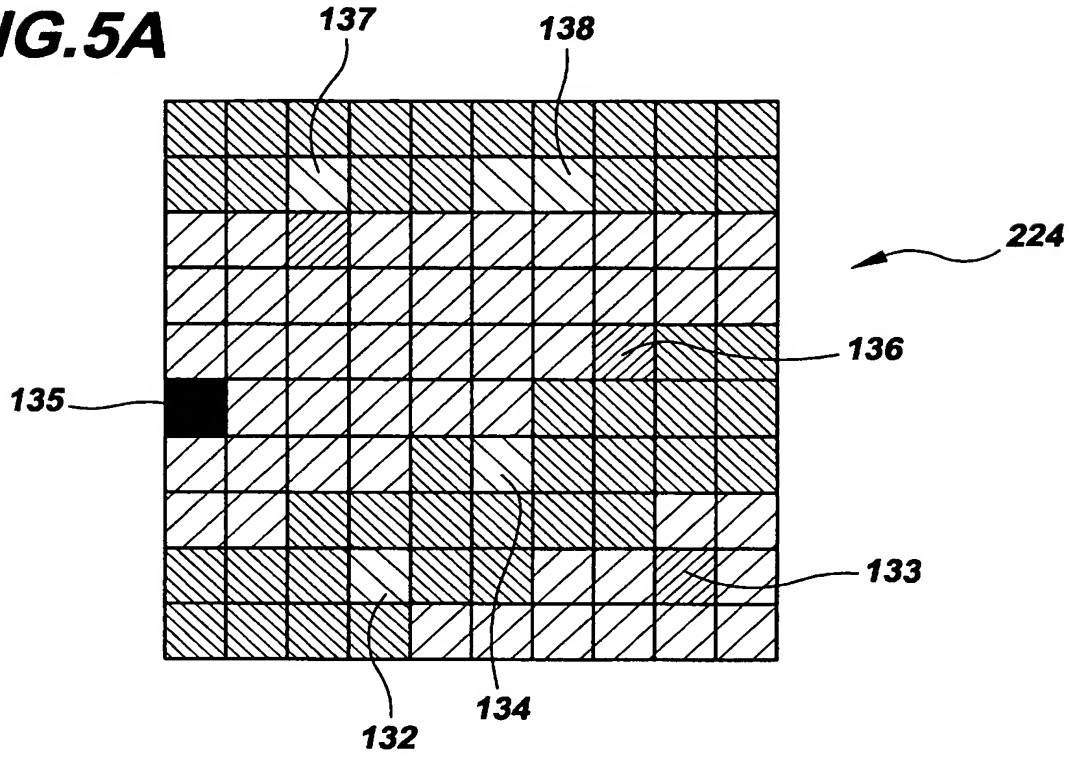

137
138
224
136
135
133
134
132

FIG.5B

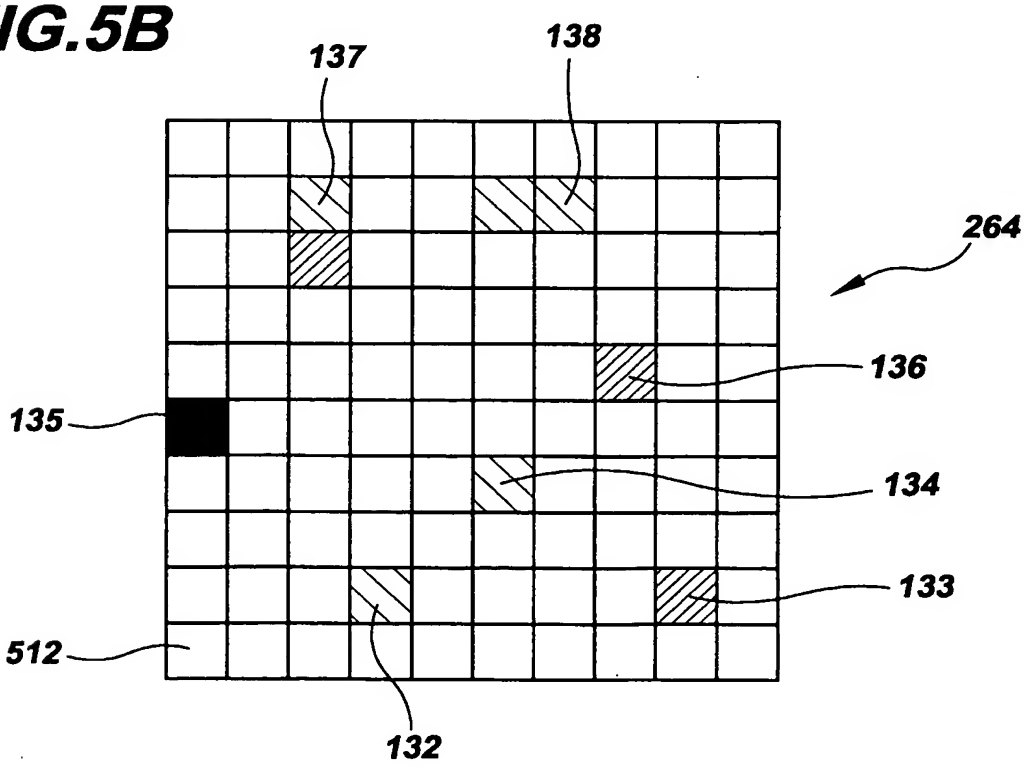

137
138
264
136
135
134
133
512
132

FIG.6A

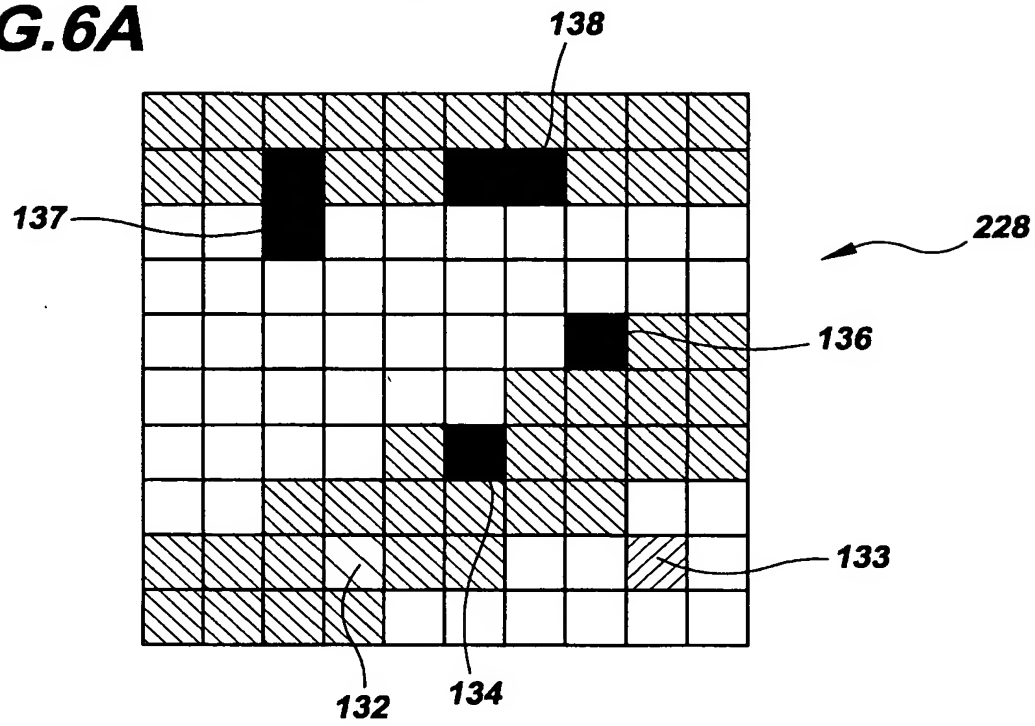


FIG.6B

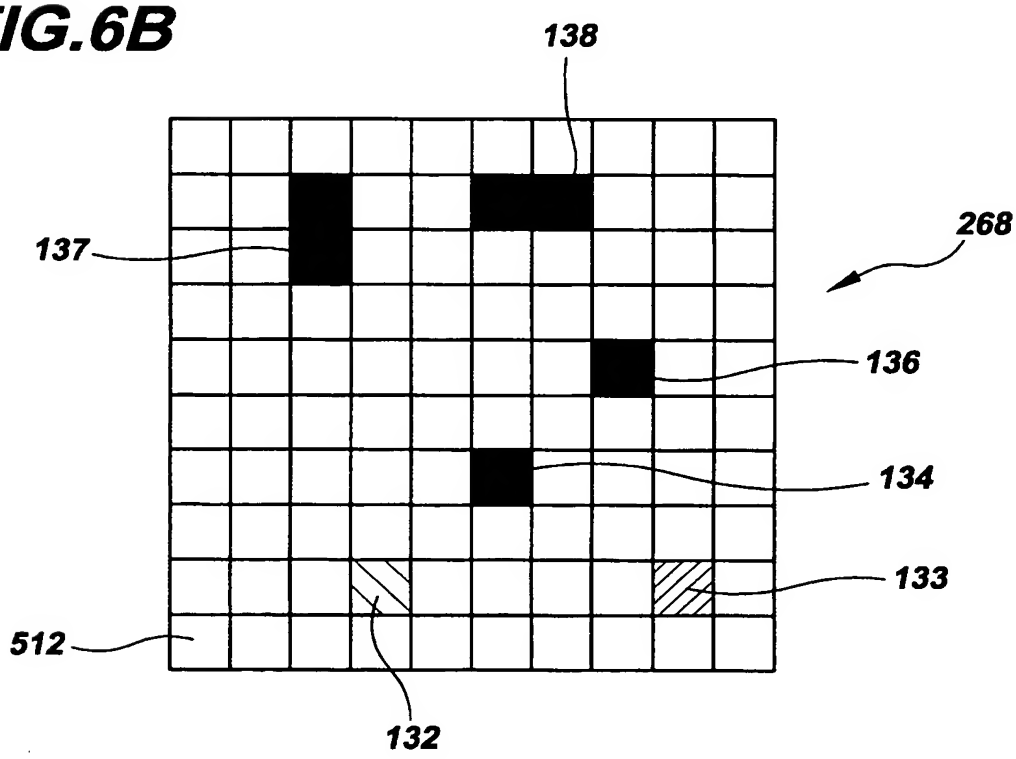


FIG.7

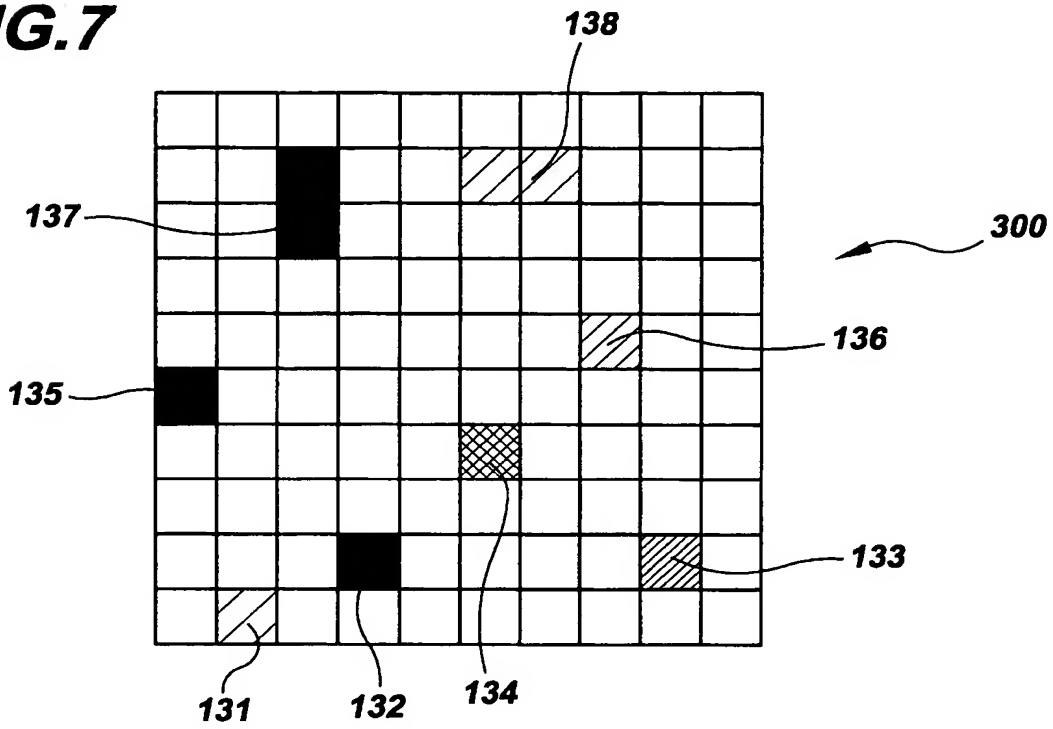


FIG.8

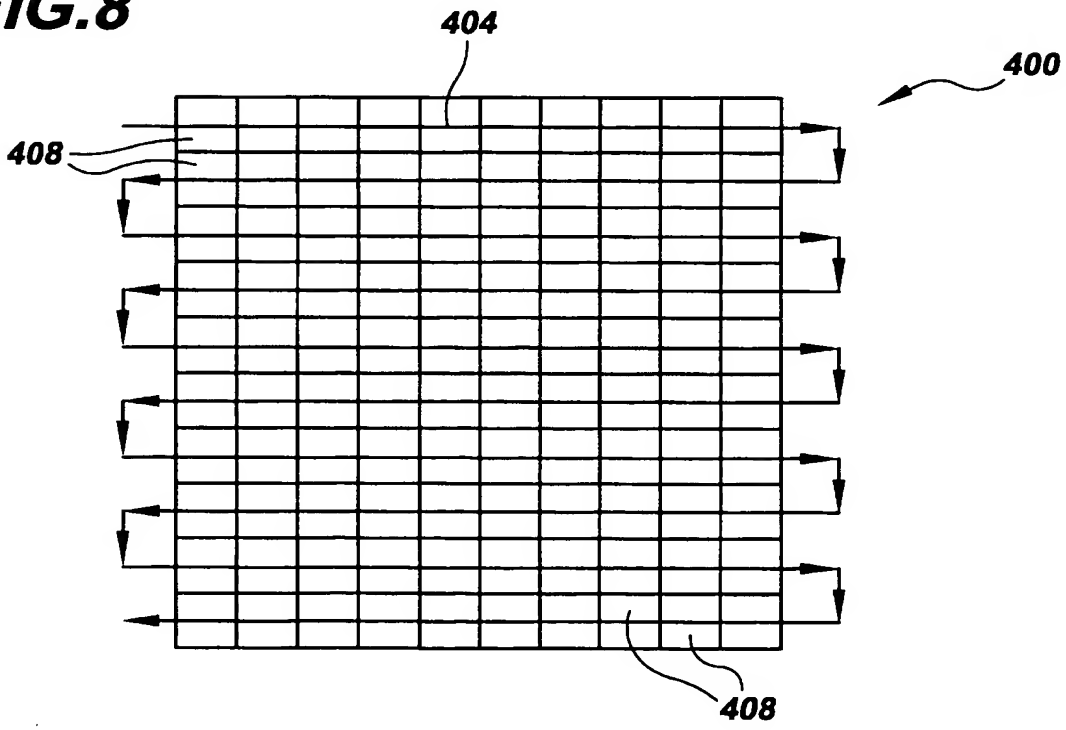
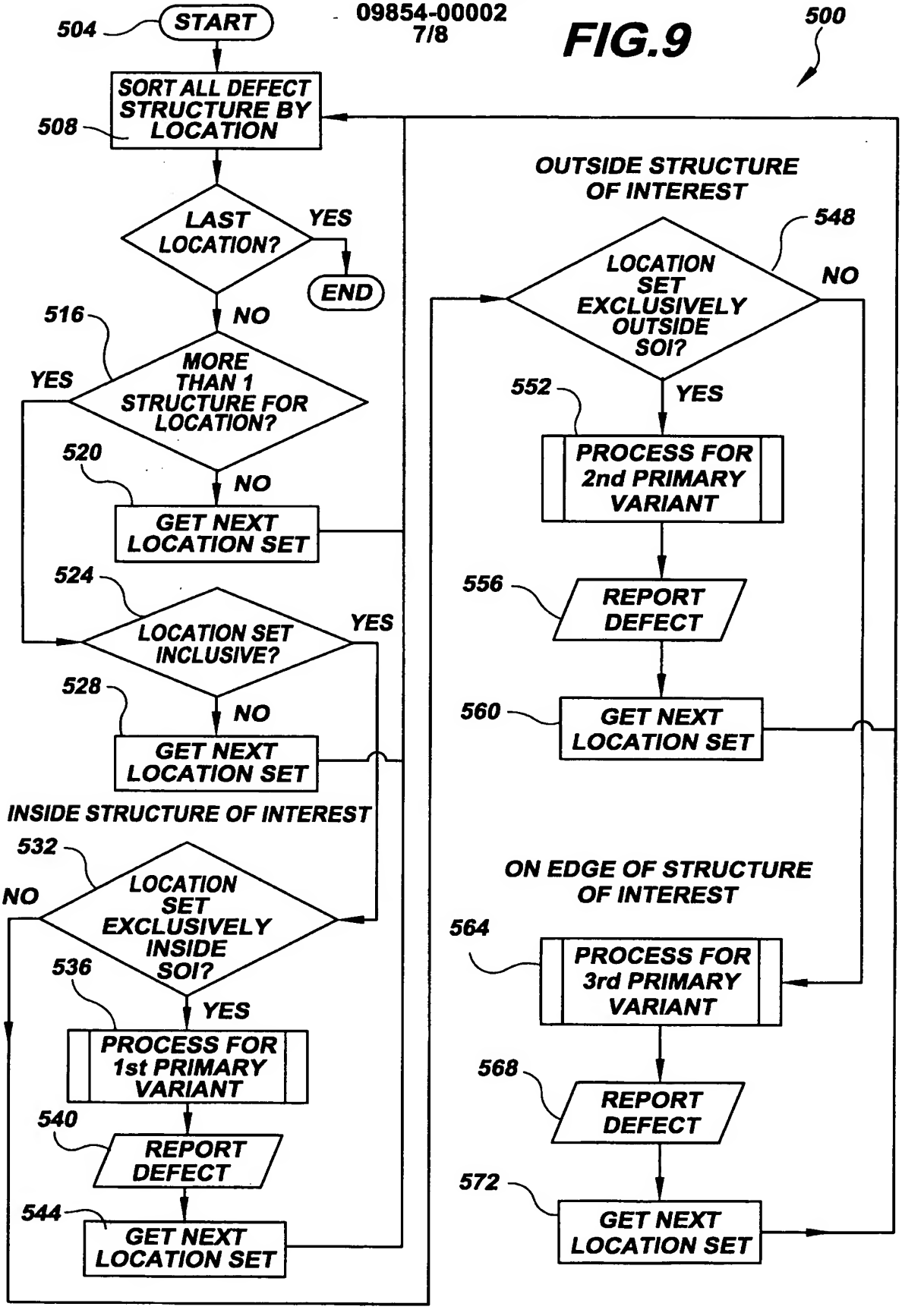


FIG.9


500
504
START
508
SORT ALL DEFECT STRUCTURE BY LOCATION
LAST LOCATION?
YES
END
NO
516
MORE THAN 1 STRUCTURE FOR LOCATION?
YES
NO
520
GET NEXT LOCATION SET
524
LOCATION SET INCLUSIVE?
YES
NO
528
GET NEXT LOCATION SET
INSIDE STRUCTURE OF INTEREST
532
LOCATION SET EXCLUSIVELY INSIDE SOI?
NO
YES
536
PROCESS FOR 1st PRIMARY VARIANT
540
REPORT DEFECT
544
GET NEXT LOCATION SET
OUTSIDE STRUCTURE OF INTEREST
548
LOCATION SET EXCLUSIVELY OUTSIDE SOI?
NO
YES
552
PROCESS FOR 2nd PRIMARY VARIANT
556
REPORT DEFECT
560
GET NEXT LOCATION SET
ON EDGE OF STRUCTURE OF INTEREST
564
PROCESS FOR 3rd PRIMARY VARIANT
568
REPORT DEFECT
572
GET NEXT LOCATION SET

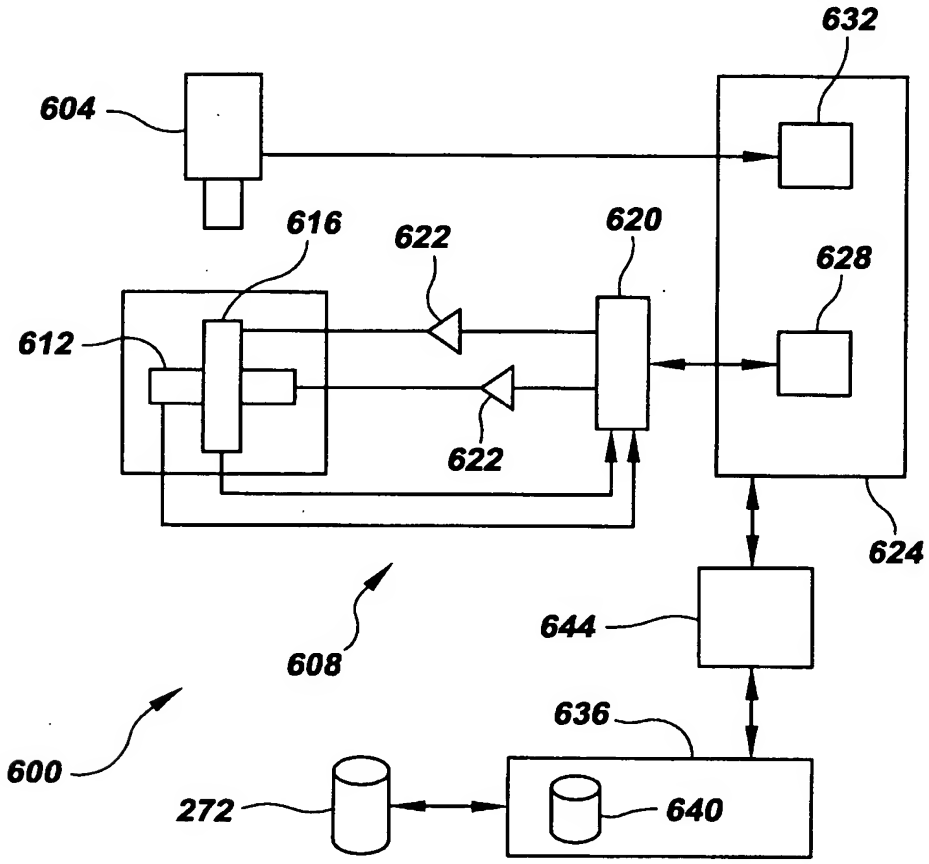



FIG. 10